

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Guy T. Blalock

Serial No.: 10/663,587

Filed: September 16, 2003

For: PLASMA PROBE, METHODS FOR
FABRICATING THE SAME, AND
METHODS FOR USING THE SAME

Confirmation No.: Unknown

Examiner: Unknown

Group Art Unit: Unknown

Attorney Docket No.: 2269-4716US
(00-0991.00/US)

CERTIFICATE OF MAILING

I hereby certify that this correspondence along with any attachments referred to or identified as being attached or enclosed is being deposited with the United States Postal Service as First Class Mail on the date of deposit shown below with sufficient postage and in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

December 2, 2003
Date

Signature

Deidra Pfeil

Name (Type/Print)

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with the duty to disclose information material to patentability pursuant to 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 or PTO/SB/08 be considered by the Examiner and made of record. Copies of the listed documents are enclosed pursuant to 37 C.F.R. § 1.98(a).

In accordance with 37 C.F.R. § 1.97(g) and (h), filing of this Information Disclosure Statement is not to be construed as a representation that a search has been made or an admission that the information cited herein is, or is considered to be, material to patentability as defined in

37 C.F.R. § 1.56(b). Further, no representation is made by Applicant herein that no other possible material information as defined in 37 C.F.R. § 1.56(b) exists.

U.S. Patent Documents

<u>U.S. Patent No.</u>	<u>Publication Date</u>	<u>Patentee</u>
US - 5,065,201	11/12/1991	Yamauchi
US - 5,315,145	05/24/1994	Lukaszek
US - 5,594,328	01/14/1997	Lukaszek
US - 6,051,443	04/18/2000	Ghio et al.
US - 6,140,833	10/31/2000	Flietner et al.
US - 6,144,037	11/07/2000	Ryan et al.

Other Documents

BOEDO, J., "UCSD-FERP Boundary Diagnostics for NSTX," NSTX PAC Meeting, May 1997, 6 pages.
 "Fast Reciprocating Probes for Edge Profile Characterization on NSTX," January 1998, 1 page.
 LUKASZEK et al., "CHARM: A New Wafer Surface Charge Monitor, TechCon '90, San Jose, 4 pages.
 MOYER, Rick, "Langmuir Probes and Boundary Plasma Measurements," DIII-D News, <http://fusion.gat.com/DNT/DNT21.htm>, August 1994, 3 pages.
 MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-11.
 MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-12.
 MOYER, Rick, "UC San Diego Fluctuation and Turbulent Transport Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-8.
 RUDAKOV, D.L. et al., "Probe Diagnostics," <http://www.rsphysse.anu.edu.au/prl/probht.html>, date unknown, 4 pages.

Applicant offers to supply any explanation or discussion of the documents that the Examiner feels is necessary or desirable and which is requested.

Serial No. 10/663,587

This Information Disclosure Statement is filed within three (3) months of the filing date of the above-identified application, and no certification pursuant to 37 C.F.R. § 1.97(c) or a fee pursuant to 37 C.F.R. § 1.17(p) is required.

Respectfully submitted,



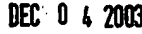
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Date: December 2, 2003

BGP/dlm:djp

Enclosures: Form PTO-1449 or PTO/SB/08
Cited Documents

Document in ProLaw



Approved for use through 10/31/2002. OMB 0651-0031

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Complete if Known

Application Number	10/663,587
Filing Date	September 16, 2003
First Named Inventor	Guy T. Blalock
Group Art Unit	Unknown
Examiner Name	Unknown
Attorney Docket Number	2269-4716US (00-0991.00/US)

Sheet	1	of	2
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Date Considered

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

2

of

2

Complete if Known

Application Number

10/663,587

Filing Date

September 16, 2003

First Named Inventor

Guy T. Blalock

Group Art Unit

Unknown

Examiner Name

Unknown

Attorney Docket Number

2269-4716US (00-0991 00/US)

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		BOEDO, J., "UCSD-FERP Boundary Diagnostics for NSTX," NSTX PAC Meeting, May 1997, 6 pages.	
		"Fast Reciprocating Probes for Edge Profile Characterization on NSTX," January 1998, 1 page.	
		LUKASZEK et al., "CHARM: A New Wafer Surface Charge Monitor, TechCon '90, San Jose, 4 pages.	
		MOYER, Rick, "Langmuir Probes and Boundary Plasma Measurements," DIII-D News, http://fusion.gat.com/DNT/DNT21.htm , August 1994, 3 pages.	
		MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-11.	
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		MOYER, Rick, "UC San Diego Fluctuation and Turbulent Transport Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-8.	
		RUDAKOV, D.L. et al., "Probe Diagnostics," http://www.rsphysse.anu.edu.au/prl/probht.html , date unknown, 4 pages.	

Examiner
SignatureDate
Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

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